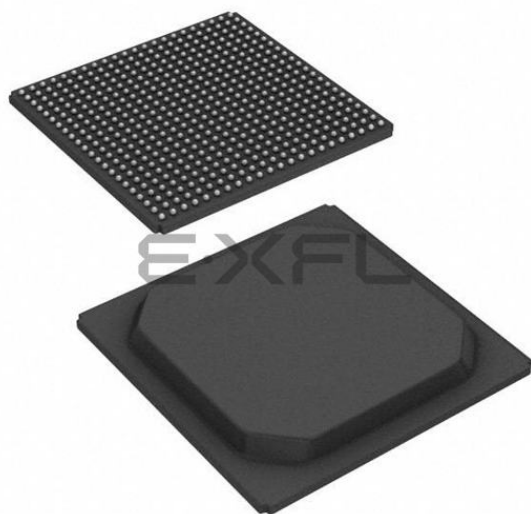




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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	300000
Total RAM Bits	21094400
Number of I/O	284
Number of Gates	-
Voltage - Supply	0.97V ~ 1.08V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BBGA, FCBGA
Supplier Device Package	484-FCBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/mpf300ts-1fcvg484i

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2 Overview

This datasheet describes PolarFire® FPGA device characteristics with industrial temperature range (–40 °C to 100 °C T_J) and extended commercial temperature range (0 °C to 100 °C T_J). The devices are provided with a standard speed grade (STD) and a –1 speed grade with higher performance. The FPGA core supply V_{DD} can operate at 1.0 V for lower-power or 1.05 V for higher performance. Similarly, the transceiver core supply V_{DDA} can also operate at 1.0 V or 1.05 V. Users select the core operating voltage while creating the Libero project.

3 References

The following documents are recommended references. For more information about PolarFire static and dynamic power data, see the [PolarFire Power Estimator Spreadsheet](#).

- [PO0137](#): PolarFire FPGA Product Overview
- [ER0217](#): PolarFire FPGA Pre-Production Device Errata
- [UG0722](#): PolarFire FPGA Packaging and Pin Descriptions Users Guide
- [UG0726](#): PolarFire FPGA Board Design User Guide
- [UG0686](#): PolarFire FPGA User I/O User Guide
- [UG0680](#): PolarFire FPGA Fabric User Guide
- [UG0714](#): PolarFire FPGA Programming User Guide
- [UG0684](#): PolarFire FPGA Clocking Resources User Guide
- [UG0687](#): PolarFire FPGA 1G Ethernet Solutions User Guide
- [UG0727](#): PolarFire FPGA 10G Ethernet Solutions User Guide
- [UG0748](#): PolarFire FPGA Low Power User Guide
- [UG0676](#): PolarFire FPGA DDR Memory Controller User Guide
- [UG0743](#): PolarFire FPGA Debugging User Guide
- [UG0725](#): PolarFire FPGA Device Power-Up and Resets User Guide
- [UG0677](#): PolarFire FPGA Transceiver User Guide
- [UG0685](#): PolarFire FPGA PCI Express User Guide
- [UG0753](#): PolarFire FPGA Security User Guide
- [UG0752](#): PolarFire FPGA Power Estimator User Guide

Parameter	Symbol	Min	Typ	Max	Unit
Transceiver TX and RX lanes supply at 1.05 V mode (when any lane rate is greater than 10.3125 Gbps) ¹	V _{DDA}	1.02	1.05	1.08	V
Programming and HSIO receiver supply	V _{DD18}	1.71	1.80	1.89	V
FPGA core and FPGA PLL high-voltage supply	V _{DD25}	2.425	2.50	2.575	V
Transceiver PLL high-voltage supply	V _{DDA25}	2.425	2.50	2.575	V
Transceiver reference clock supply –3.3 V nominal	V _{DD_XCVR_CLK}	3.135	3.3	3.465	V
Transceiver reference clock supply –2.5 V nominal	V _{DD_XCVR_CLK}	2.375	2.5	2.625	V
Global V _{REF} for transceiver reference clocks ³	XCVR _{VREF}	Ground		V _{DD_XCVR_CLK}	V
HSIO DC I/O supply. Allowed nominal options: 1.2 V, 1.35 V, 1.5 V, and 1.8 V ⁴	V _{DDI_x}	1.14	Various	1.89	V
GPIO DC I/O supply. Allowed nominal options: 1.2 V, 1.5 V, 1.8 V, 2.5 V, and 3.3 V ^{2,4}	V _{DDI_x}	1.14	Various	3.465	V
Dedicated I/O DC supply for JTAG and SPI (GPIO Bank 3). Allowed nominal options: 1.8 V, 2.5 V, and 3.3 V	V _{DDI3}	1.71	Various	3.465	V
GPIO auxiliary supply for I/O bank x with V _{DDI_x} = 3.3 V nominal ^{2,4}	V _{DDAUX_x}	3.135	3.3	3.465	V
GPIO auxiliary supply for I/O bank x with V _{DDI_x} = 2.5 V nominal or lower ^{2,4}	V _{DDAUX_x}	2.375	2.5	2.625	V
Extended commercial temperature range	T _J	0		100	°C
Industrial temperature range	T _J	–40		100	°C
Extended commercial programming temperature range	T _{PRG}	0		100	°C
Industrial programming temperature range	T _{PRG}	–40		100	°C

1. V_{DD} and V_{DDA} can independently operate at 1.0 V or 1.05 V nominal. These supplies are not dynamically adjustable.
2. For GPIO buffers where I/O bank is designated as bank number, if V_{DDI_x} is 2.5 V nominal or 3.3 V nominal, V_{DDAUX_x} must be connected to the V_{DDI_x} supply for that bank. If V_{DDI_x} for a given GPIO bank is <2.5 V nominal, V_{DDAUX_x} per I/O bank must be powered at 2.5 V nominal.
3. XCVR_{VREF} globally sets the reference voltage of the transceiver's single-ended reference clock input buffers. It is typically near V_{DD_XCVR_CLK}/2 V but is allowed in the specified range.
4. The power supplies for a given I/O bank x are shown as VDDI_x and VDDAUX_x.

The maximum overshoot duration is specified as a high-time percentage over the lifetime of the device. A DC signal is equivalent to 100% of the duty-cycle.

The following table shows the maximum AC input voltage (V_{IN}) overshoot duration for HSIO.

Table 6 • Maximum Overshoot During Transitions for HSIO

AC (V_{IN}) Overshoot Duration as % at $T_J = 100\text{ }^{\circ}\text{C}$	Condition (V)
100	1.8
100	1.85
100	1.9
100	1.95
100	2
100	2.05
100	2.1
100	2.15
100	2.2
90	2.25
30	2.3
7.5	2.35
1.9	2.4

Note: Overshoot level is for VDDI at 1.8 V.

The following table shows the maximum AC input voltage (V_{IN}) undershoot duration for HSIO.

Table 7 • Maximum Undershoot During Transitions for HSIO

AC (V_{IN}) Undershoot Duration as % at $T_J = 100\text{ }^{\circ}\text{C}$	Condition (V)
100	-0.05
100	-0.1
100	-0.15
100	-0.2
100	-0.25
100	-0.3
100	-0.35
100	-0.4
44	-0.45
14	-0.5
4.8	-0.55
1.6	-0.6

The following table shows the maximum AC input voltage (V_{IN}) overshoot duration for GPIO.

Note: The following dedicated pins do not support hot socketing: TMS, TDI, TRSTB, DEVRST_N, and FF_EXIT_N. Weak pull-up (as specified in GPIO) is always enabled.

6.3 Input and Output

The following section describes:

- DC I/O levels
- Differential and complementary differential DC I/O levels
- HSIO and GPIO on-die termination specifications
- LVDS specifications

6.3.1 DC Input and Output Levels

The following tables list the DC I/O levels.

Table 12 • DC Input Levels

I/O Standard	V _{DDI} Min (V)	V _{DDI} Typ (V)	V _{DDI} Max (V)	V _{IL} Min (V)	V _{IL} Max (V)	V _{IH} Min (V)	V _{IH} ¹ Max (V)
PCI	3.15	3.3	3.45	−0.3	0.3 x V _{DDI}	0.5 x V _{DDI}	3.45
LVTTL	3.15	3.3	3.45	−0.3	0.8	2	3.45
LVC MOS33	3.15	3.3	3.45	−0.3	0.8	2	3.45
LVC MOS25	2.375	2.5	2.625	−0.3	0.7	1.7	2.625
LVC MOS18	1.71	1.8	1.89	−0.3	0.35 x V _{DDI}	0.65 x V _{DDI}	1.89
LVC MOS15	1.425	1.5	1.575	−0.3	0.35 x V _{DDI}	0.65 x V _{DDI}	1.575
LVC MOS12	1.14	1.2	1.26	−0.3	0.35 x V _{DDI}	0.65 x V _{DDI}	1.26
SSTL25I ²	2.375	2.5	2.625	−0.3	V _{REF} − 0.15	V _{REF} + 0.15	2.625
SSTL25II ²	2.375	2.5	2.625	−0.3	V _{REF} − 0.15	V _{REF} + 0.15	2.625
SSTL18I ²	1.71	1.8	1.89	−0.3	V _{REF} − 0.125	V _{REF} + 0.125	1.89
SSTL18II ²	1.71	1.8	1.89	−0.3	V _{REF} − 0.125	V _{REF} + 0.125	1.89
SSTL15I	1.425	1.5	1.575	−0.3	V _{REF} − 0.1	V _{REF} + 0.1	1.575
SSTL15II	1.425	1.5	1.575	−0.3	V _{REF} − 0.1	V _{REF} + 0.1	1.575

I/O Standard	V _{DDI} Min (V)	V _{DDI} Typ (V)	V _{DDI} Max (V)	V _{OL} Min (V)	V _{OL} Max (V)	V _{OH} Min (V)	V _{OH} Max (V)	I _{OL} ^{2,6} mA	I _{OH} ^{2,6} mA
HSTL135I ⁴	1.283	1.35	1.418		0.2 x V _{DDI}	0.8 x V _{DDI}		V _{OL} /50	(V _{DDI} – V _{OH}) /50
HSTL135II ⁴	1.283	1.35	1.418		0.2 x V _{DDI}	0.8 x V _{DDI}		V _{OL} /25	(V _{DDI} – V _{OH}) /25
HSTL12I ⁴	1.14	1.2	1.26		0.1 x V _{DDI}	0.9 x V _{DDI}		V _{OL} /50	(V _{DDI} – V _{OH}) /50
HSTL12II ⁴	1.14	1.2	1.26		0.1 x V _{DDI}	0.9 x V _{DDI}		V _{OL} /25	(V _{DDI} – V _{OH}) /25
HSUL18I ⁴	1.71	1.8	1.89		0.1 x V _{DDI}	0.9 x V _{DDI}		V _{OL} /55	(V _{DDI} – V _{OH}) /55
HSUL18II ⁴	1.71	1.8	1.89		0.1 x V _{DDI}	0.9 x V _{DDI}		V _{OL} /25	(V _{DDI} – V _{OH}) /25
HSUL12I ⁴	1.14	1.2	1.26		0.1 x V _{DDI}	0.9 x V _{DDI}		V _{OL} /40	(V _{DDI} – V _{OH}) /40
POD12I ^{4,5}	1.14	1.2	1.26		0.5 x V _{DDI}			V _{OL} /48	(V _{DDI} – V _{OH}) /48
POD12II ^{4,5}	1.14	1.2	1.26		0.5 x V _{DDI}			V _{OL} /34	(V _{DDI} – V _{OH}) /34

1. Drive strengths per PCI specification V/I curves.
2. Refer to [UG0686: PolarFire FPGA User I/O User Guide](#) for details on supported drive strengths.
3. For external stub-series resistance. This resistance is on-die for GPIO.
4. I_{OL}/I_{OH} units for impedance standards in amps (not mA).
5. V_{OH}_MAX based on external pull-up termination (pseudo-open drain).
6. The total DC sink/source current of all IOs within a lane is limited as follows:
 - a. HSIO lane: 120 mA per 12 IO buffers.
 - b. GPIO lane: 160 mA per 12 IO buffers.

Note: 3.3 V and 2.5 V are only supported in GPIO banks.

6.3.2 Differential DC Input and Output Levels

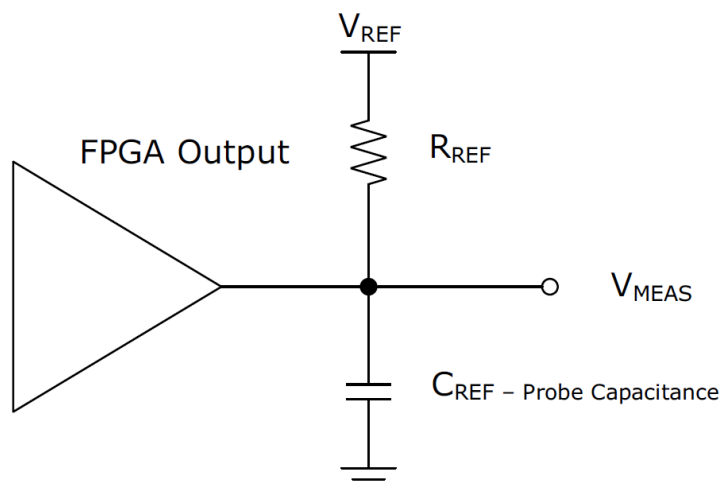
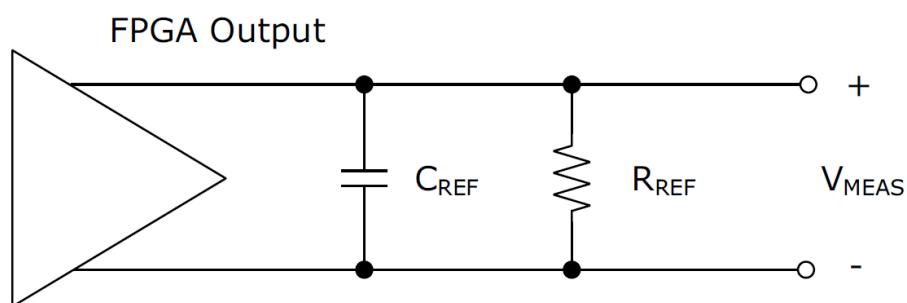
The follow tables list the differential DC I/O levels.

Table 14 • Differential DC Input Levels

I/O Standard	Bank Type	VICM_RANGE Libero Setting	V _{ICM} ^{1,3} Min (V)	V _{ICM} ^{1,3} Typ (V)	V _{ICM} ^{1,3} Max (V)	V _{ID} ² Min (V)	V _{ID} Typ (V)	V _{ID} Max (V)
LVDS33	GPIO	Mid (default)	0.6	1.25	2.35	0.1	0.35	0.6
		Low	0.05	0.4	0.8	0.1	0.35	0.6
LVDS25	GPIO	Mid (default)	0.6	1.25	2.35	0.1	0.35	0.6
		Low	0.05	0.4	0.8	0.1	0.35	0.6
LVDS18 ⁴	GPIO	Mid (default)	0.6	1.25	1.65	0.1	0.35	0.6

Standard	Description	V_I^1	V_H^1	V_{ID}^2	V_{ICM}^2	$V_{MEAS}^{3,4}$	$V_{REF}^{1,5}$	Unit
HSUL18I	HSUL 1.8 V Class I	$V_{REF} -$ 0.54	$V_{REF} +$ 0.54			V_{REF}	0.90	V
HSUL18II	HSUL 1.8 V Class II	$V_{REF} -$ 0.54	$V_{REF} +$ 0.54			V_{REF}	0.90	V
HSUL12	HSUL 1.2 V	$V_{REF} -$.22	$V_{REF} +$.22			V_{REF}	0.60	V
POD12I	Pseudo open drain (POD) logic 1.2 V Class I	$V_{REF} -$.15	$V_{REF} +$.15			V_{REF}	0.84	V
POD12II	POD 1.2 V Class II	$V_{REF} -$.15	$V_{REF} +$.15			V_{REF}	0.84	V
LVDS33	Low-voltage differential signaling (LVDS) 3.3 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	1.250	0		V
LVDS25	LVDS 2.5 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	1.250	0		V
LVDS18	LVDS 1.8 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	0.900	0		V
RSDS33	RSDS 3.3 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	1.250	0		V
RSDS25	RSDS 2.5 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	1.250	0		V
RSDS18	RSDS 1.8 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	1.250	0		V
MINILVDS33	Mini-LVDS 3.3 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	1.250	0		V
MINILVDS25	Mini-LVDS 2.5 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	1.250	0		V
MINILVDS18	Mini-LVDS 1.8 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	1.250	0		V
SUBLVDS33	Sub-LVDS 3.3 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	0.900	0		V
SUBLVDS25	Sub-LVDS 2.5 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	0.900	0		V
SUBLVDS18	Sub-LVDS 1.8 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	0.900	0		V
PPDS33	Point-to-point differential signaling 3.3 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	0.800	0		V
PPDS25	PPDS 2.5 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	0.800	0		V
PPDS18	PPDS 1.8 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	0.800	0		V
SLVS33	Scalable low- voltage signaling 3.3 V	$V_{ICM} -$.125	$V_{ICM} +$.125	0.250	0.200	0		V

Standard	Description	V_L^1	V_H^1	V_{ID}^2	V_{ICM}^2	$V_{MEAS}^{3,4}$	$V_{REF}^{1,5}$	Unit
SLVS25	SLVS 2.5 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.200	0		V
SLVS18	SLVS 1.8 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.200	0		V
HCSL33	High-speed current steering logic (HCSL) 3.3 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.350	0		V
HCSL25	HCSL 2.5 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.350	0		V
HCSL18	HCSL 1.8 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.350	0		V
BLVDSE25 ⁶	Bus LVDS 2.5 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.250	0		V
MLVDSE25 ⁶	Multipoint LVDS 2.5 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.250	0		V
LVPECL33	Low-voltage positive emitter coupled logic	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.650	0		V
LVPECL33 ⁶	Low-voltage positive emitter coupled logic	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.650	0		V
SSTL25I	Differential SSTL 2.5 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.250	0		V
SSTL25II	Differential SSTL 2.5 V Class II	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.250	0		V
SSTL18I	Differential SSTL 1.8 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.900	0		V
SSTL18II	Differential SSTL 1.8 V Class II	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.900	0		V
SSTL15	Differential SSTL 1.5 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.750	0		V
SSTL135	Differential SSTL 1.5 V Class II	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.750	0		V
HSTL15I	Differential HSTL 1.5 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.750	0		V
HSTL15II	Differential HSTL 1.5 V Class II	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.750	0		V
HSTL135I	Differential HSTL 1.35 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.675	0		V

Figure 1 • Output Delay Measurement—Single-Ended Test Setup

Figure 2 • Output Delay Measurement—Differential Test Setup


7.1.3 Input Buffer Speed

The following tables provide information about input buffer speed.

Table 24 • HSIO Maximum Input Buffer Speed

Standard	STD	-1	Unit
LVDS18	1250	1250	Mbps
RDS18	800	800	Mbps
MINILVDS18	800	800	Mbps
SUBLVDS18	800	800	Mbps
PPDS18	800	800	Mbps
SLVS18	800	800	Mbps
SSTL18I	800	1066	Mbps
SSTL18II	800	1066	Mbps
SSTL15I	1066	1333	Mbps
SSTL15II	1066	1333	Mbps
SSTL135I	1066	1333	Mbps
SSTL135II	1066	1333	Mbps

Standard	STD	–1	Unit
HSTL15I	900	1100	Mbps
HSTL15II	900	1100	Mbps
HSTL135I	1066	1066	Mbps
HSTL135II	1066	1066	Mbps
HSUL18I	400	400	Mbps
HSUL18II	400	400	Mbps
HSUL12	1066	1333	Mbps
HSTL12	1066	1266	Mbps
POD12I	1333	1600	Mbps
POD12II	1333	1600	Mbps
LVCMS18 (12 mA)	500	500	Mbps
LVCMS15 (10 mA)	500	500	Mbps
LVCMS12 (8 mA)	300	300	Mbps

1. Performance is achieved with $V_{ID} \geq 200$ mV.

Table 25 • GPIO Maximum Input Buffer Speed

Standard	STD	–1	Unit
LVDS25/LVDS33/LCMDS25/LCMDS33	1250	1600	Mbps
RSDS25/RSDS33	800	800	Mbps
MINILVDS25/MINILVDS33	800	800	Mbps
SUBLVDS25/SUBLVDS33	800	800	Mbps
PPDS25/PPDS33	800	800	Mbps
SLVS25/SLVS33	800	800	Mbps
SLVSE15	800	800	Mbps
HCSL25/HCSL33	800	800	Mbps
BUSLVDSE25	800	800	Mbps
MLVDSE25	800	800	Mbps
LVPECL33	800	800	Mbps
SSTL25I	800	800	Mbps
SSTL25II	800	800	Mbps
SSTL18I	800	800	Mbps
SSTL18II	800	800	Mbps
SSTL15I	800	1066	Mbps
SSTL15II	800	1066	Mbps
HSTL15I	800	900	Mbps
HSTL15II	800	900	Mbps
HSUL18I	400	400	Mbps
HSUL18II	400	400	Mbps
PCI	500	500	Mbps
LVTTTL33 (20 mA)	500	500	Mbps
LVCMS33 (20 mA)	500	500	Mbps
LVCMS25 (16 mA)	500	500	Mbps

Standard	STD	–1	Unit
LVC MOS18 (12 mA)	500	500	Mbps
LVC MOS15 (10 mA)	500	500	Mbps
LVC MOS12 (8 mA)	300	300	Mbps
MIPI25/MIPI33	800	800	Mbps

1. All SSTLD/HSTLD/HSULD/LVSTLD/POD type receivers use the LVDS differential receiver.
2. Performance is achieved with $V_{ID} \geq 200$ mV.

7.1.4 Output Buffer Speed

Table 26 • HSIO Maximum Output Buffer Speed

Standard	STD	–1	Unit
SSTL18I	800	1066	Mbps
SSTL18II	800	1066	Mbps
SSTL18I (differential)	800	1066	Mbps
SSTL18II (differential)	800	1066	Mbps
SSTL15I	1066	1333	Mbps
SSTL15II	1066	1333	Mbps
SSTL15I (differential)	1066	1333	Mbps
SSTL15II (differential)	1066	1333	Mbps
SSTL135I	1066	1333	Mbps
SSTL135II	1066	1333	Mbps
SSTL135I (differential)	1066	1333	Mbps
SSTL135II (differential)	1066	1333	Mbps
HSTL15I	900	1100	Mbps
HSTL15II	900	1100	Mbps
HSTL15I (differential)	900	1100	Mbps
HSTL15II (differential)	900	1100	Mbps
HSTL135I	1066	1066	Mbps
HSTL135II	1066	1066	Mbps
HSTL135I (differential)	1066	1066	Mbps
HSTL135II (differential)	1066	1066	Mbps
HSUL18I	400	400	Mbps
HSUL18II	400	400	Mbps
HSUL18II (differential)	400	400	Mbps
HSUL12	1066	1333	Mbps
HSUL12I (differential)	1066	1333	Mbps
HSTL12	1066	1266	Mbps
HSTL12I (differential)	1066	1266	Mbps
POD12I	1333	1600	Mbps
POD12II	1333	1600	Mbps
LVC MOS18 (12 mA)	500	500	Mbps
LVC MOS15 (10 mA)	500	500	Mbps

7.1.6 User I/O Switching Characteristics

The following section describes characteristics for user I/O switching.

For more information about user I/O timing, see the *PolarFire I/O Timing Spreadsheet* (to be released).

7.1.6.1 I/O Digital

The following tables provide information about I/O digital.

Table 30 • I/O Digital Receive Single-Data Rate Switching Characteristics

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Clock-to-Data Condition
F _{MAX}	RX_SDR_G_A	Rx SDR							MHz	From a global clock source, aligned
F _{MAX}	RX_SDR_L_A	Rx SDR							MHz	From a lane clock source, aligned
F _{MAX}	RX_SDR_G_C	Rx SDR							MHz	From a global clock source, centered
F _{MAX}	RX_SDR_L_C	Rx SDR							MHz	From a lane clock source, centered

Table 31 • I/O Digital Receive Double-Data Rate Switching Characteristics

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Clock-to-Data Condition
F _{MAX}	RX_DDR_G_A	Rx DDR		335			335	MHz	MHz	From a global clock source, aligned
F _{MAX}	RX_DDR_L_A	Rx DDR		250			250		MHz	From a lane clock source, aligned
F _{MAX}	RX_DDR_G_C	Rx DDR		335			335		MHz	From a global clock source, centered
F _{MAX}	RX_DDR_L_C	Rx DDR		250			250		MHz	From a lane clock source, centered
F _{MAX} 2:1	RX_DDRX_B_A	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Clock-to-Data Condition
F _{MAX} 8:1	RX_DDRX_BL_C	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered

Table 32 • I/O Digital Transmit Single-Data Rate Switching Characteristics

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Forwarded Clock-to-Data Skew
Output F _{MAX}	TX_SDR_G_A	Tx SDR							MHz	From a global clock source, aligned ¹
	TX_SDR_G_C	Tx SDR							MHz	From a global clock source, centered ¹

1. A centered clock-to-data interface can be created with a negedge launch of the data.

Table 33 • I/O Digital Transmit Double-Data Rate Switching Characteristics

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Forwarded Clock-to-Data Skew
Output F _{MAX}	TX_DDR_G_A	Tx DDR			335			335	MHz	From a global clock source, aligned
	TX_DDR_G_C	Tx DDR			335			335	MHz	From a global clock source, centered
	TX_DDR_L_A	Tx DDR			250			250	MHz	From a lane clock source, aligned
	TX_DDR_L_C	Tx DDR			250			250	MHz	From a lane clock source, centered
Output F _{MAX} 2:1	TX_DDRX_B_A	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
Output F _{MAX} 4:1	TX_DDRX_B_A	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
Output F _{MAX} 8:1	TX_DDRX_B_A	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned

Parameter	Symbol	Min	Typ	Max	Unit
Operating current (V_{DD18})	RC_{SCVPP}			0.1	μA
Operating current (V_{DD})	RC_{SCVDD}			60.7	μA

Table 52 • PolarFire Transceiver Transmitter Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Condition
Differential termination	V_{TERM}		85		Ω	
	V_{TERM}		100		Ω	
	V_{TERM}		150		Ω	
Common mode voltage ¹	V_{OCM}	$0.44 \times V_{\text{DDA}}$	$0.525 \times V_{\text{DDA}}$	$0.59 \times V_{\text{DDA}}$	V	DC coupled 50% setting
	V_{OCM}	$0.52 \times V_{\text{DDA}}$	$0.6 \times V_{\text{DDA}}$	$0.66 \times V_{\text{DDA}}$	V	DC coupled 60% setting
	V_{OCM}	$0.61 \times V_{\text{DDA}}$	$0.7 \times V_{\text{DDA}}$	$0.75 \times V_{\text{DDA}}$	V	DC coupled 70% setting
	V_{OCM}	$0.63 \times V_{\text{DDA}}$	$0.8 \times V_{\text{DDA}}$	$0.83 \times V_{\text{DDA}}$	V	DC coupled 80% setting
Rise time ²	T_{TXRF}	41		70	ps	20% to 80%
Fall time ²		41		70	ps	80% to 20%
Differential peak-to-peak amplitude	V_{ODPP}		1040		mV	1000 mV setting
	V_{ODPP}		840		mV	800 mV setting
	V_{ODPP}		630		mV	600 mV setting
	V_{ODPP}		620		mV	500 mV setting
	V_{ODPP}		530		mV	400 mV setting
	V_{ODPP}		360		mV	300 mV setting
	V_{ODPP}		240		mV	200 mV setting
	V_{ODPP}		160		mV	100 mV setting
Transmit lane P to N skew ³	T_{OSKEW}		8	15	ps	
Lane to lane transmit skew ⁴	T_{LLSKEW}			75	ps	Single PLL
					ps	Multiple PLL
Electrical idle transition entry time ⁷	$T_{\text{TxElTrEntry}}$				ns	
Electrical idle transition exit time ⁷	$T_{\text{TxElTrExit}}$				ns	
Electrical idle amplitude	V_{TxElpp}				mV	
TXPLL lock time	T_{TXLock}			1600	PFD cycles	
Digital PLL lock time ⁸	T_{DPLLlock}				REFCLK UIs	
Total jitter ^{5,6}	T_{J}				UI	Data rate ≥ 8.5 Gbps to 12.7 Gbps ⁹
Deterministic jitter ^{5,6}	T_{DJ}				UI	(Tx V_{CO} rate 4.25 GHz to 6.35 GHz)
Total jitter ^{5,6}	T_{J}			0.28	UI	Data rate ≥ 3.2 Gbps to 8.5 Gbps
Deterministic jitter ^{5,6}	T_{DJ}			0.07	UI	(Tx V_{CO} rate 2.5 GHz to 5.0 GHz)
Total jitter ^{5,6}	T_{J}			0.28	UI	Data rate ≥ 1.6 Gbps to 3.2 Gbps
Deterministic jitter ^{5,6}	T_{DJ}			0.07	UI	(Tx V_{CO} rate 2.5 GHz to 5.0 GHz)
Total jitter ^{5,6}	T_{J}			0.13	UI	Data rate ≥ 800 Mbps to 1.6 Gbps
Deterministic jitter ^{5,6}	T_{DJ}			0.02	UI	(Tx V_{CO} rate 2.5 GHz to 5.0 GHz)
Total jitter ^{5,6}	T_{J}			0.06	UI	Data rate = 250 Mbps to 800 Mbps
Deterministic jitter ^{5,6}	T_{DJ}			0.01	UI	(Tx V_{CO} rate 2.5 GHz to 5.0 GHz)

1. Increased DC common mode settings above 50% reduce allowed V_{OD} output swing capabilities.
2. Adjustable through transmit emphasis.
3. With estimated package differences.
4. Single PLL applies to all four lanes in the same quad location with the same TxPLL.

Table 55 • PCI Express Gen2

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter	5.0 Gbps		0.35	UI
Receiver jitter tolerance	5.0 Gbps	0.4		UI

Note: With add-in card as specified in PCI Express CEM Rev 2.0.

7.5.2 Interlaken

The following table describes Interlaken.

Table 56 • Interlaken

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter	6.375 Gbps		0.3	UI
	10.3125 Gbps		0.3	UI
	12.7 Gbps ¹			UI
Receiver jitter tolerance	6.375 Gbps	0.6		UI
	10.3125 Gbps	0.65		UI
	12.7 Gbps ¹			UI

- For data rates greater than 10.3125 Gbps, VDDA must be set to 1.05 V mode. See supply tolerance in the section [Recommended Operating Conditions](#) (see page 6).

7.5.3 10GbE (10GBASE-R, and 10GBASE-KR)

The following table describes 10GbE (10GBASE-R).

Table 57 • 10GbE (10GBASE-R)

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter	10.3125 Gbps		0.28	UI
Receiver jitter tolerance	10.3125 Gbps	0.7		UI

The following table describes 10GbE (10GBASE-KR).

Table 58 • 10GbE (10GBASE-KR)

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter	10.3125 Gbps			UI
Receiver jitter tolerance	10.3125 Gbps			UI

The following table describes 10GbE (XAUI).

Table 59 • 10GbE (XAUI)

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter (near end)	3.125 Gbps		0.35	UI
Total transmit jitter (far end)			0.55	UI
Receiver jitter tolerance	3.125 Gbps	0.65		UI

The following table describes 10GbE (RXAUI).

Parameter	Symbol	Typ	Max	Unit
Time from negation of RESPONSE to all I/Os re-enabled	T _{CLR_IO_DISABLE}	28	38	μs
Time from triggering the response to security locked	T _{LOCKDOWN}			ns
Time from negation of RESPONSE to earlier security unlock condition	T _{CLR_LOCKDOWN}			ns
Time from triggering the response to device enters RESET	T _{tr_RESET}	11.7	14	μs
Time from triggering the response to start of zeroization	T _{tr_ZEROLISE}	7.4	8.2	ms

7.8.5 System Controller Suspend Switching Characteristics

The following table describes the characteristics of system controller suspend switching.

Table 95 • System Controller Suspend Entry and Exit Characteristics

Parameter	Symbol	Definition	Typ	Max	Unit
Time from TRSTb falling edge to SUSPEND_EN signal assertion	T _{suspend_tr} ^{1,2}	Suspend entry time from TRST_N assertion	42	44	ns
Time from TRSTb rising edge to ACTIVE signal assertion	T _{suspend_exit}	Suspend exit time from TRST_N negation	361	372	ns

1. ACTIVE indicates that the system controller is inactive or active regardless of the state of SUSPEND_EN.
2. ACTIVE signal must never be asserted with SUSPEND_EN is asserted.

7.8.6 Dynamic Reconfiguration Interface

The following table provides interface timing information for the DRI, which is an embedded APB slave interface within the FPGA fabric that does not use FPGA resources.

Table 96 • Dynamic Reconfiguration Interface Timing Characteristics

Parameter	Symbol	Max	Unit
PCLK frequency	F _{PD_PCLK}	200	MHz

7.9 Power-Up to Functional Timing

Microsemi non-volatile FPGA technology offers the fastest boot-time of any mid-range FPGA in the market. The following tables describes both cold-boot (from power-on) and warm-boot (assertion of DEVRST_N pin or assertion of reset from the tamper macro) timing. The power-up diagrams assume all power supplies to the device are stable.

7.9.1 Power-On (Cold) Reset Initialization Sequence

The following cold reset timing diagram shows the initialization sequencing of the device.

Table 107 • SPI Master Mode (PolarFire Master) During Device Initialization

Parameter	Symbol	Min	Typ	Max	Unit	Condition
SCK frequency	F _{MSCK}			40	MHz	

Table 108 • SPI Slave Mode (PolarFire Slave)

Parameter	Symbol	Min	Typ	Max	Unit	Condition
SCK frequency	F _{SSCK}			80	MHz	

7.10.3 SmartDebug Probe Switching Characteristics

The following table describes characteristics of SmartDebug probe switching.

Table 109 • SmartDebug Probe Performance Characteristics

Parameter	Symbol	V _{DD} = 1.0 V STD	V _{DD} = 1.0 V – 1	V _{DD} = 1.05 V STD	V _{DD} = 1.05 V – 1	Unit
Maximum frequency of probe signal	F _{MAX}	100	100	100	100	MHz
Minimum delay of probe signal	T _{Min_delay}	13	12	13	12	ns
Maximum delay of probe signal	T _{Max_delay}	13	12	13	12	ns

7.10.4 DEVRST_N Switching Characteristics

The following table describes characteristics of DEVRST_N switching.

Table 110 • DEVRST_N Electrical Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Condition
DEVRST_N ramp rate	DR _{RAMP}		10		μs	It must be a normal clean digital signal, with typical rise and fall times
DEVRST_N assert time	DR _{ASSERT}	1			μs	The minimum time for DEVRST_N assertion to be recognized
DEVRST_N de-assert time	DR _{DEASSERT}	2.75			ms	The minimum time DEVRST_N needs to be de-asserted before assertion

7.10.5 FF_EXIT Switching Characteristics

The following table describes characteristics of FF_EXIT switching.

Table 111 • FF_EXIT Electrical Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Condition
FF_EXIT_N ramp rate	FF _{RAMP}		10		μs	
Minimum FF_EXIT_N assert time	FF _{ASSERT}	1			μs	The minimum time for FF_EXIT_N to be recognized
Minimum FF_EXIT_N de-assert time	FF _{DEASSERT}	170			μs	The minimum time FF_EXIT_N needs to be de-asserted before assertion

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